

Application/Control	No.
10/042,846	

Reexamination HAIMOVSKY ET AL.

Applicant(s)/Patent under

Examiner Tse Chen Art Unit 2116

				ISSUE	CL	.AS	SIF	ICATI	ON						
		ORIGINAL	INTERNATIONAL CLASSIFICATION												
CLASS SUBCL				LASS	S CLAIMED						N	NON-CLAIMED			
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	CROS	S REFERE	NCES						,				,		
CLASS	SUBCLA	ASS (ONE S	UBCLASS PE	R BLOCK)					,						
713	1	100							1				1		
709	221	222							1				1 ·		
710	104								1				1		
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(Assistant Examiner) (Date)						1/14/08				Total Claims Allowed: 29					
					(Primary Examiner)			(Date)		O.G. Print Claim(s)					
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	4			34		28	64	]		94			124			154			184
	5		4	35		29	65			95			125			155			185
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